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Sheet 1 of 1



FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(37 CFR 1.98(b))

Attorney Docket No.:
EHF 2001,0167 P

Applic. No.
09/873,230

Applicant

Norbert Benesch et al.

Filing Date
June 4, 2001

Group Art Unit
2621

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
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Technology Center 2600

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
JS	J	61 169 750	07/31/86	Japan			X
JS	K	62 200 251	09/03/87	Japan			X
JS	L	9 191 032	07/22/97	Japan			X
JS	M	9 318 330	12/12/97	Japan			X
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
JS	J	60 224 041	11/08/85	Japan			X
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	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

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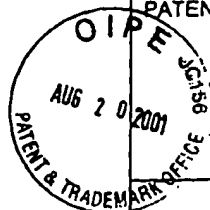
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Group Art Unit

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
JS	A	4,964,726	10/23/90	Kleinknecht et al.	_____	_____	_____
JS	B	5,703,692	12/30/97	McNeil et al.	_____	_____	_____
JS	C	5,830,611	11/03/98	Bishop et al.	_____	_____	_____
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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
JS	J	198 24 624 A1	02/25/99	Germany	_____	_____	X
JS	K	0 874 396 A2	10/28/98	Europe	_____	_____	X
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

JS	O	Scott Bushman et al.: "Scatterometry Measurements for Process Monitoring of Polysilicon Gate Etch", SPIE, vol. 32131997, pp. 79-90, XP-000890146
JS	P	Stephen A. Coulombe et al.: "Ellipsometric-Scatterometry for sub-0.1 μ m CD measurements", SPIE, vol. 3332, 1998, pp. 282-293, XP-000890148

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U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
JS	A	5,768,192	06/16/98	Eitan			
JS	B	6,011,725	01/04/00	Eitan			
JS	C	6,191,459 B1	02/20/01	Hofmann et al.			
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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	NO
	J	196 00 422 C1	08/21/97	Germany				X
	K	196 03 810 C1	08/28/97	Germany				X
	L	195 45 903 A1	06/12/97	Germany				X
	M	196 00 423 A1	07/17/97	Germany				X
JS	N	WO 99/60631	11/25/99	WIPO			X	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

JS	O	Junko Tanaka et al.: "A Sub-0.1- μ m Grooved Gate MOSFET with High Immunity to Short-Channel Effects", IEDM 93, pp. 537-540;
JS	P	Ken-ichiro Nakagawa et al.: "A Flash EEPROM Cell with Self-Aligned Trench Transistor & Isolation Structure", 2000 Symposium on VLSI Technology Digest of Technical Papers

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